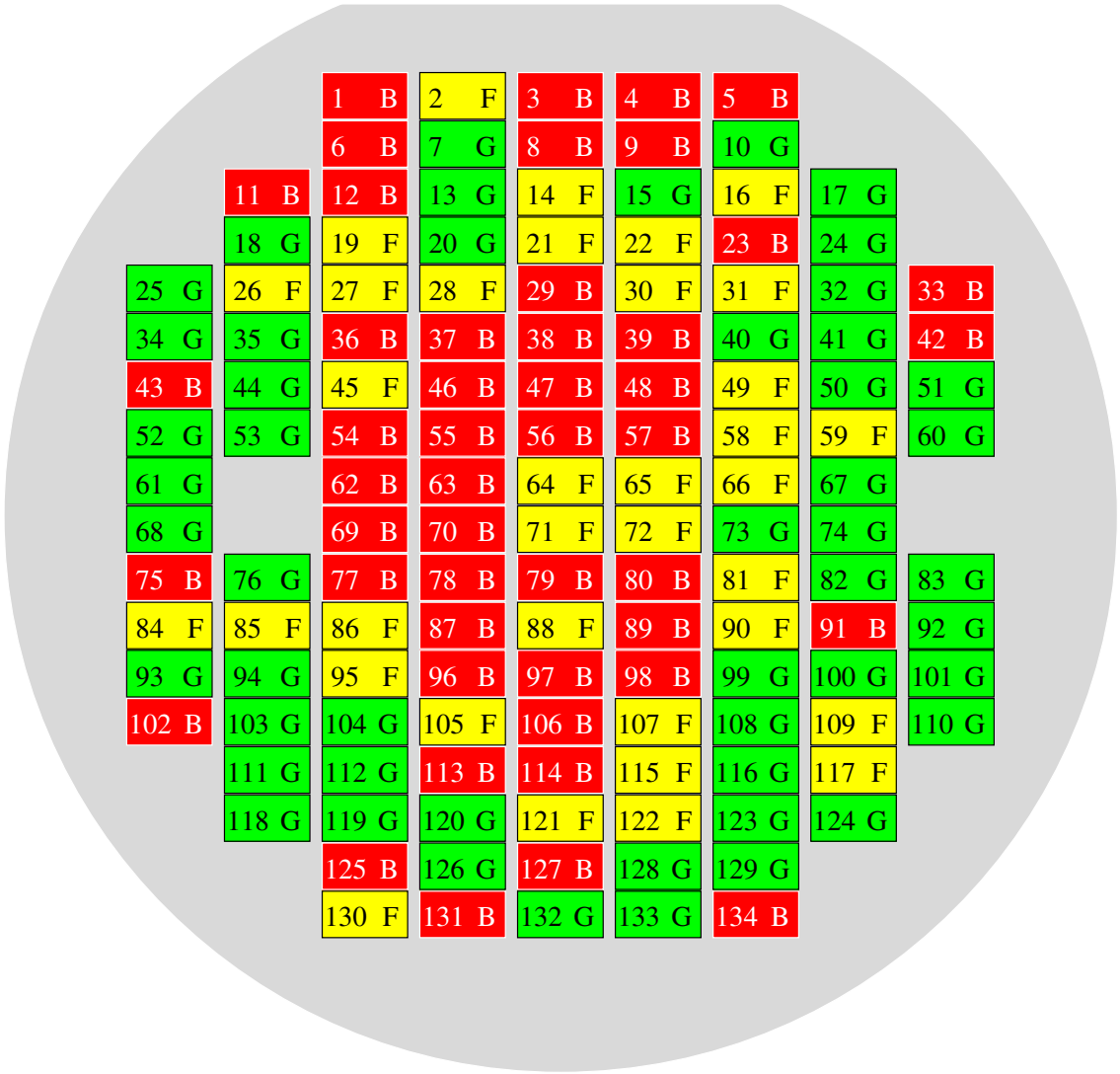
Die quality map for wafer 176 s/n: Y21316-09-19

Date: 07/08/99



# B	Bad die
# F	Fair die
# G	Good die
# N	No info
# *	Manually tagged